

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter		N Channel	P Channel	Unit
Common Ratings					
V_{DSS}	Drain-Source Voltage		20	-20	V
V_{GSS}	Gate-Source Voltage		± 12	± 12	
T_J	Maximum Junction Temperature		150		$^\circ\text{C}$
T_{STG}	Storage Temperature Range		-55 to 150		
I_S	Diode Continuous Forward Current	$T_A=25^\circ\text{C}$	1	-1	A
I_D	Continuous Drain Current	$T_A=25^\circ\text{C}$	8	-4.5	
I_{DM}^a	Pulsed Drain Current	$T_A=25^\circ\text{C}$	32	-18	
P_D	Power Dissipation	$T_A=25^\circ\text{C}$	1.8	1.8	W
		$T_A=70^\circ\text{C}$	1.1	1.1	
$R_{\theta JA}^b$	Thermal Resistance-Junction to Ambient	$t \leq 10\text{s}$	70	70	$^\circ\text{C/W}$
		Steady State	110	110	
I_{AS}^c	Avalanche Current, Single pulse	$L=0.5\text{mH}$	6	-7	A
E_{AS}^c	Avalanche Energy, Single pulse	$L=0.5\text{mH}$	9	12	mJ

Note a : Pulse width limited by max. junction temperature.

Note b : Surface Mounted on 1in^2 pad area, $t \leq 10\text{sec}$. $R_{\theta JA}$ steady state $t=999\text{s}$.

Note c : UIS tested and pulse width limited by maximum junction temperature 150°C (initial temperature $T_J=25^\circ\text{C}$).

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	N Channel			Unit
			Min.	Typ.	Max.	
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=250\mu A$	20	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=16V, V_{GS}=0V$ $T_J=85^\circ\text{C}$	-	-	1	μA
			-	-	30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	0.5	0.75	1	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 10V, V_{DS}=0V$	-	-	± 10	μA
$R_{DS(on)}^d$	Drain-Source On-state Resistance	$V_{GS}=10V, I_{DS}=8A$	-	15	18	m Ω
		$V_{GS}=4.5V, I_{DS}=7.5A$	-	17.5	22	
		$V_{GS}=2.5V, I_{DS}=6A$	-	24	32.5	
		$V_{GS}=1.8V, I_{DS}=3A$	-	42	65	
Diode Characteristics						
V_{SD}^d	Diode Forward Voltage	$I_{SD}=1A, V_{GS}=0V$	-	0.75	1	V
t_{rr}	Reverse Recovery Time	$I_{DS}=8A, di_{SD}/dt=100A/\mu s$	-	13.5	-	ns
Q_{rr}	Reverse Recovery Charge		-	3	-	nC
Dynamic Characteristics^e						
R_G	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1\text{MHz}$	-	1.6	2.6	Ω
C_{iss}	Input Capacitance	$V_{GS}=0V,$ $V_{DS}=10V,$ Frequency=1.0MHz	-	475	620	pF
C_{oss}	Output Capacitance		-	88	-	
C_{riss}	Reverse Transfer Capacitance		-	77	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=10V, R_L=10\Omega,$ $I_{DS}=1A, V_{GEN}=10V,$ $R_G=6\Omega$	-	4	8	ns
t_r	Turn-on Rise Time		-	16	29	
$t_{d(OFF)}$	Turn-off Delay Time		-	18	33	
t_f	Turn-off Fall Time		-	2	3.6	
Gate Charge Characteristics^e						
Q_g	Total Gate Charge	$V_{DS}=10V, V_{GS}=4.5V,$ $I_{DS}=8A$	-	7	10	nC
Q_{gs}	Gate-Source Charge		-	0.7	-	
Q_{gd}	Gate-Drain Charge		-	3.2	-	

Note d : Pulse test; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.

Note e : Guaranteed by design, not subject to production testing.

Electrical Characteristics (Cont.) ($T_A = 25^\circ\text{C}$ unless otherwise noted)

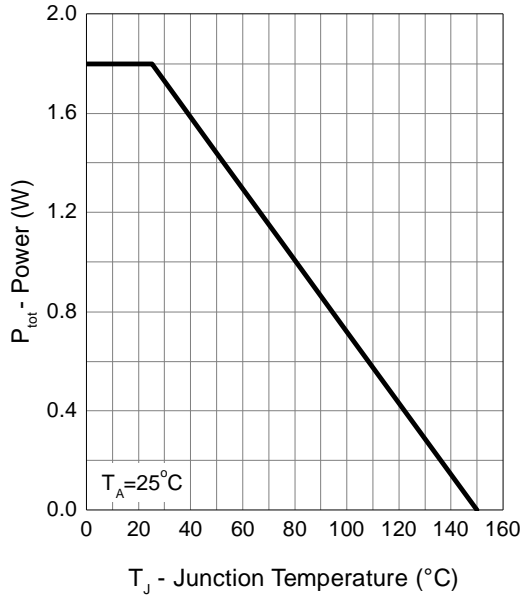
Symbol	Parameter	Test Conditions	P Channel			Unit
			Min.	Typ.	Max.	
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=-250\mu A$	-20	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-16V, V_{GS}=0V$ $T_J=85^\circ\text{C}$	-	-	-1	μA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=-250\mu A$	-0.5	-0.7	-1	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 10V, V_{DS}=0V$	-	-	± 10	μA
$R_{DS(ON)}^d$	Drain-Source On-state Resistance	$V_{GS}=-4.5V, I_{DS}=-4.5A$	-	45	60	m Ω
		$V_{GS}=-2.5V, I_{DS}=-2.5A$	-	66	90	
		$V_{GS}=-1.8V, I_{DS}=-1A$	-	102	150	
Diode Characteristics						
V_{SD}^d	Diode Forward Voltage	$I_{SD}=-1A, V_{GS}=0V$	-	-0.8	-1	V
t_{rr}	Reverse Recovery Time	$I_{sd}=-4.5A, di_{SD}/dt=100A/\mu s$	-	25	-	ns
Q_{rr}	Reverse Recovery Charge		-	11	-	nC
Dynamic Characteristics^e						
R_G	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1\text{MHz}$	-	5.5	11	Ω
C_{iss}	Input Capacitance	$V_{GS}=0V,$ $V_{DS}=-10V,$ Frequency=1.0MHz	-	468	608	pF
C_{oss}	Output Capacitance		-	110	-	
C_{riss}	Reverse Transfer Capacitance		-	98	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=-10V, R_L=15\Omega,$ $I_{DS}=-1A, V_{GEN}=-4.5V,$ $R_G=1\Omega$	-	7	13	ns
t_r	Turn-on Rise Time		-	15	27	
$t_{d(OFF)}$	Turn-off Delay Time		-	23	41	
t_f	Turn-off Fall Time		-	4	7	
Gate Charge Characteristics^e						
Q_g	Total Gate Charge	$V_{DS}=-10V, V_{GS}=-4.5V,$ $I_{DS}=-4.5A$	-	9.6	13	nC
Q_{gs}	Gate-Source Charge		-	1.1	-	
Q_{gd}	Gate-Drain Charge		-	2.6	-	
Q_{gth}	Threshold Gate Charge		-	1.1	-	

Note d : Pulse test; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.

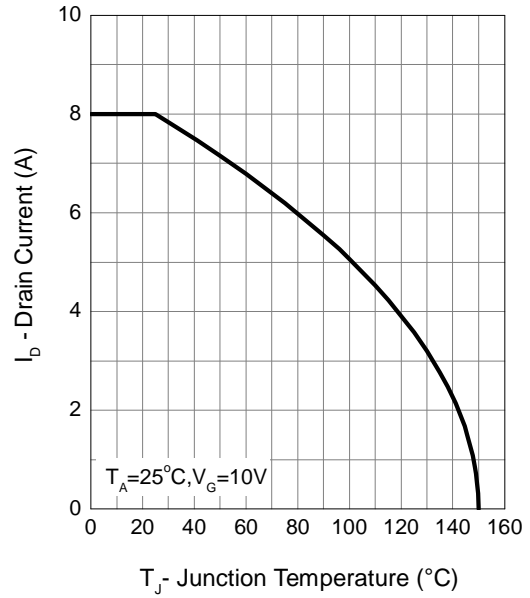
Note e : Guaranteed by design, not subject to production testing.

N Channel Typical Operating Characteristics

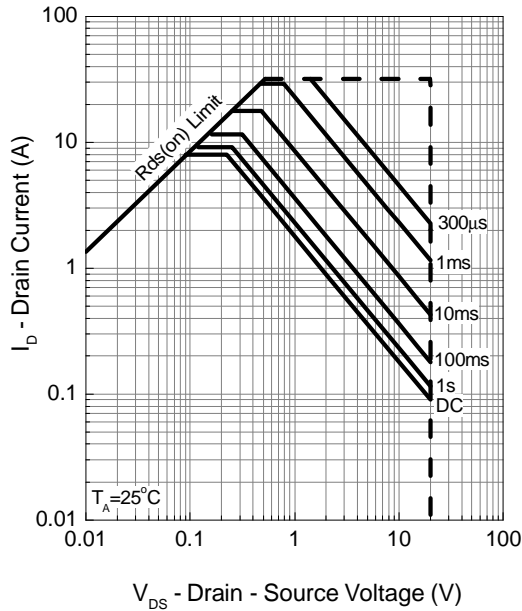
Power Dissipation



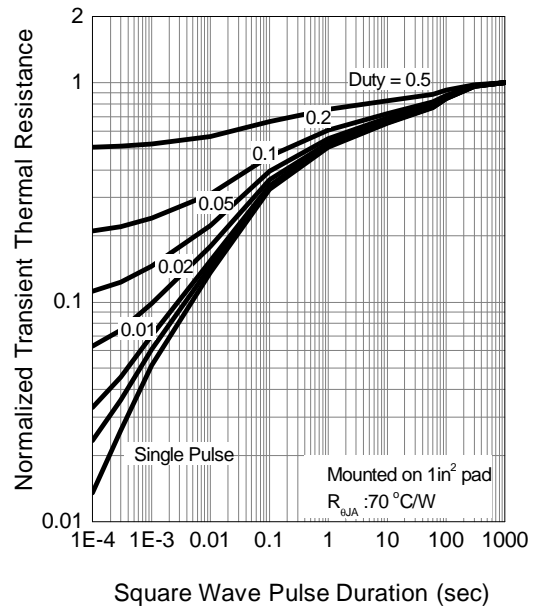
Drain Current



Safe Operation Area

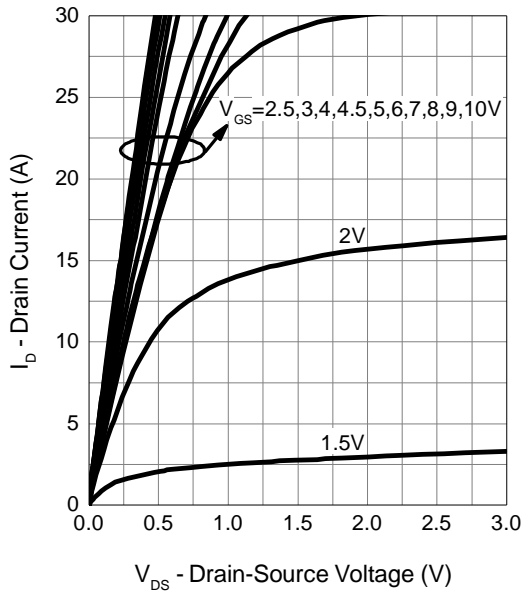


Thermal Transient Impedance

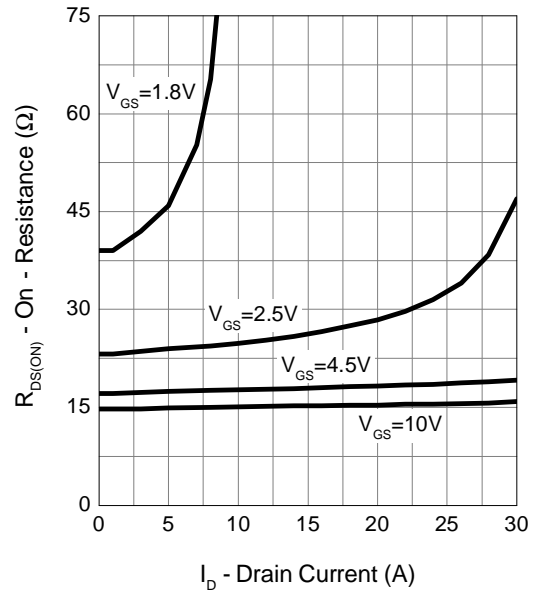


N Channel Typical Operating Characteristics (Cont.)

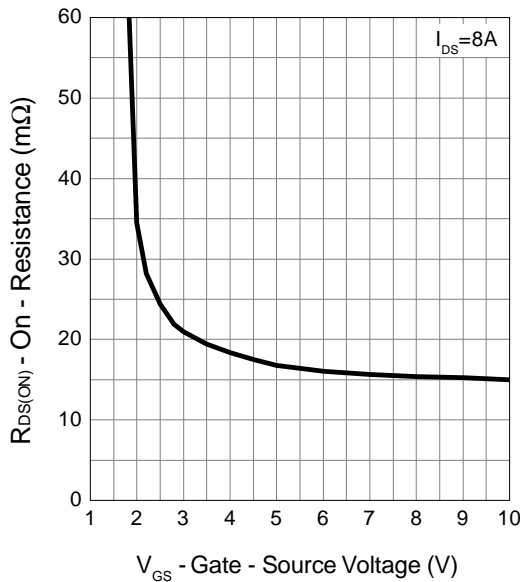
Output Characteristics



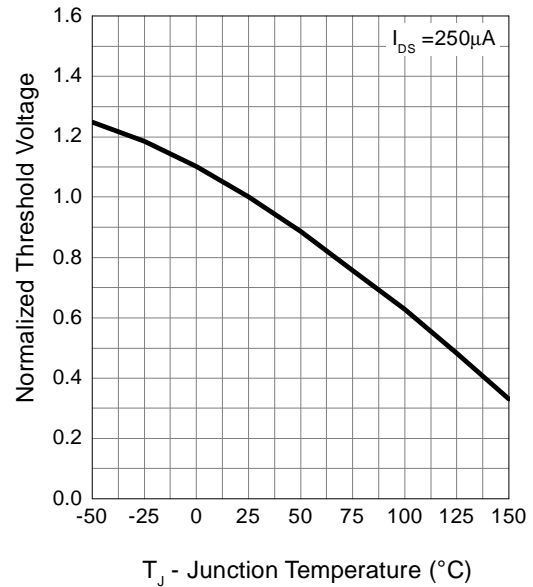
Drain-Source On Resistance



Transfer Characteristics

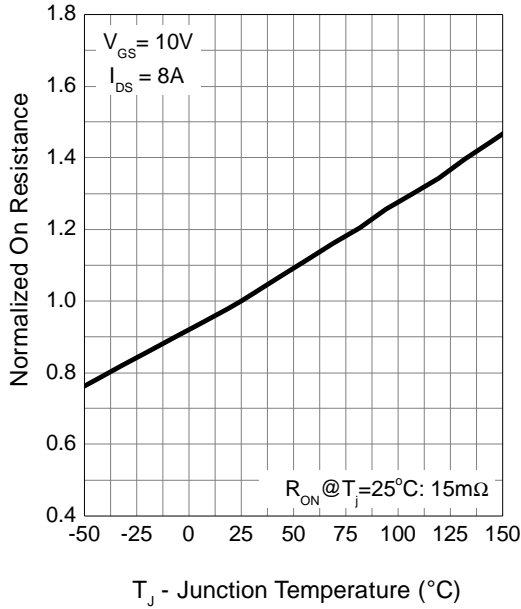


Gate Threshold Voltage

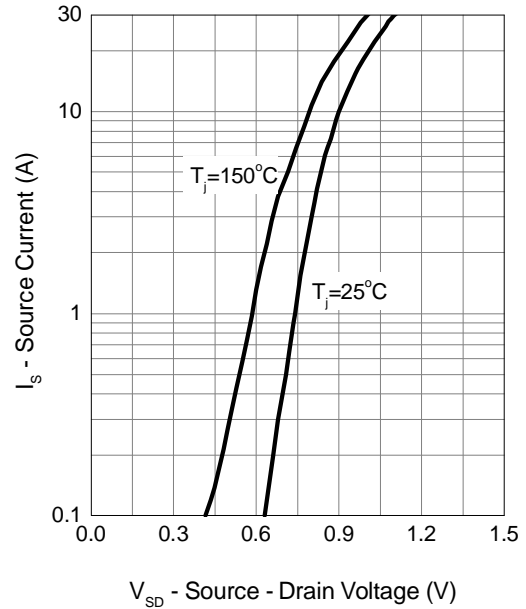


N Channel Typical Operating Characteristics (Cont.)

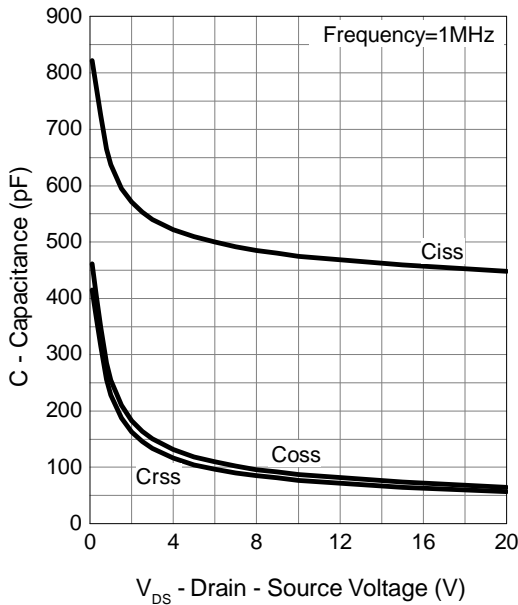
Drain-Source On Resistance



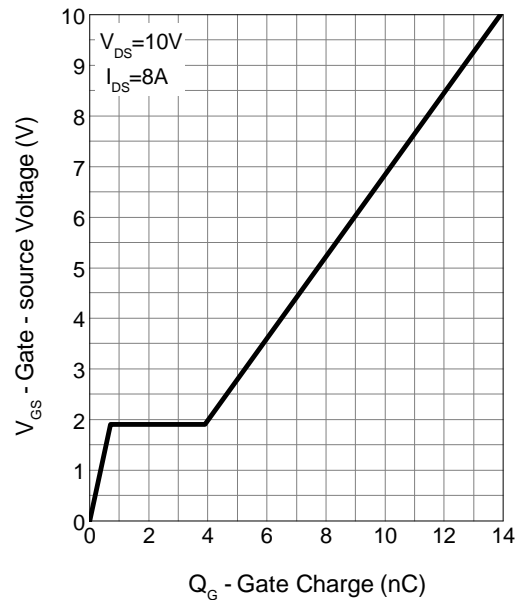
Source-Drain Diode Forward



Capacitance

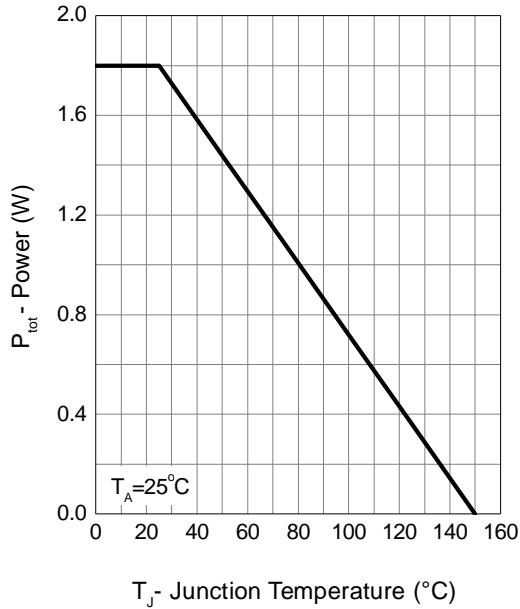


Gate Charge

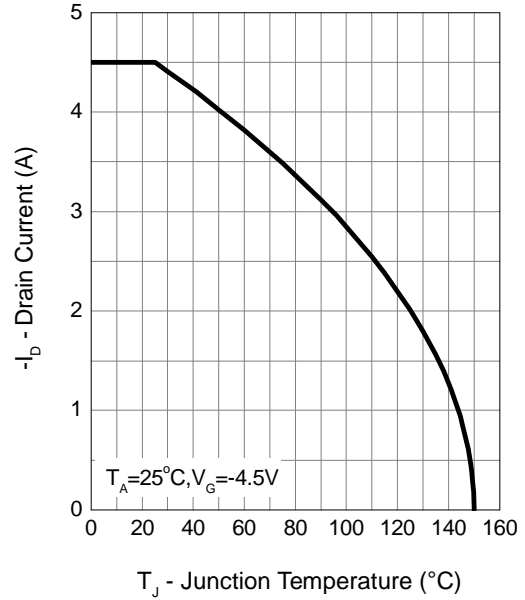


P Channel Typical Operating Characteristics

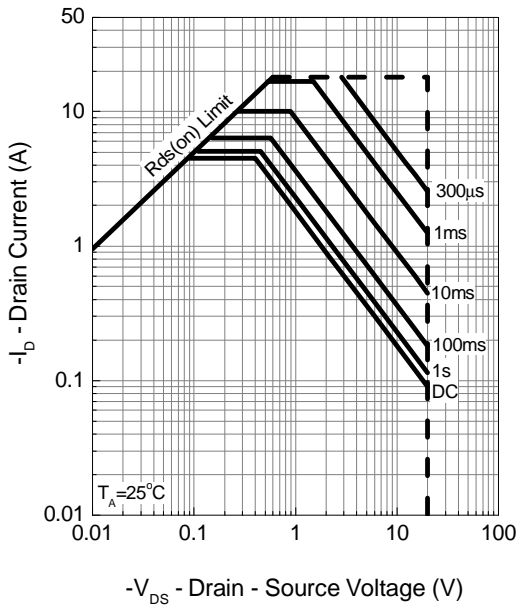
Power Dissipation



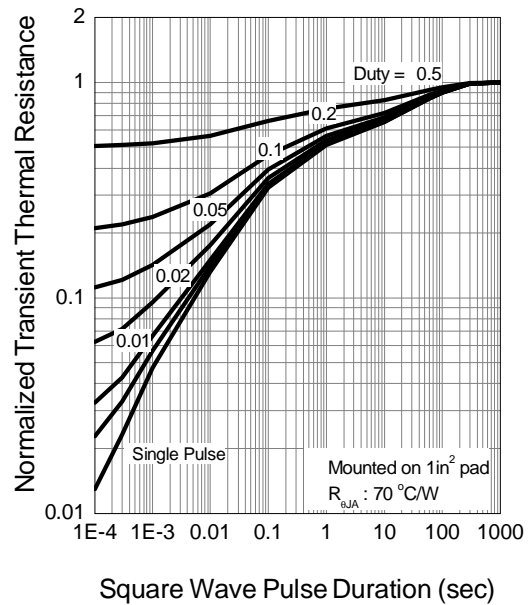
Drain Current



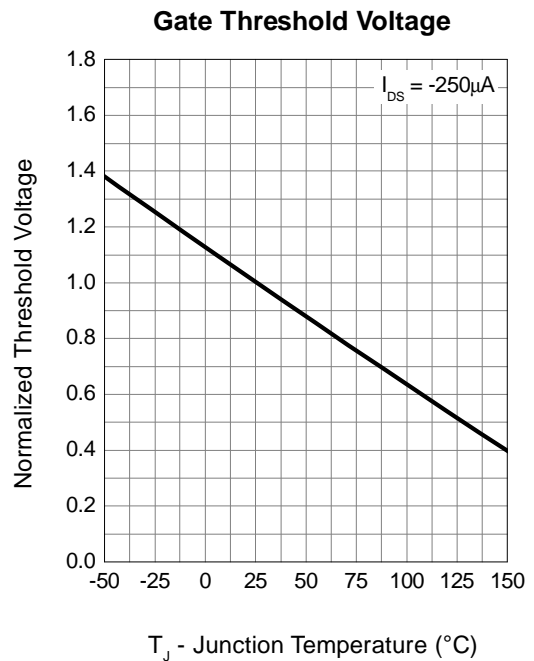
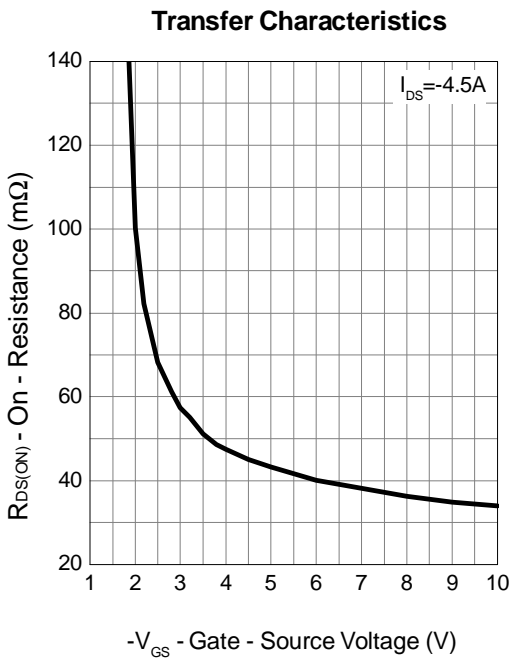
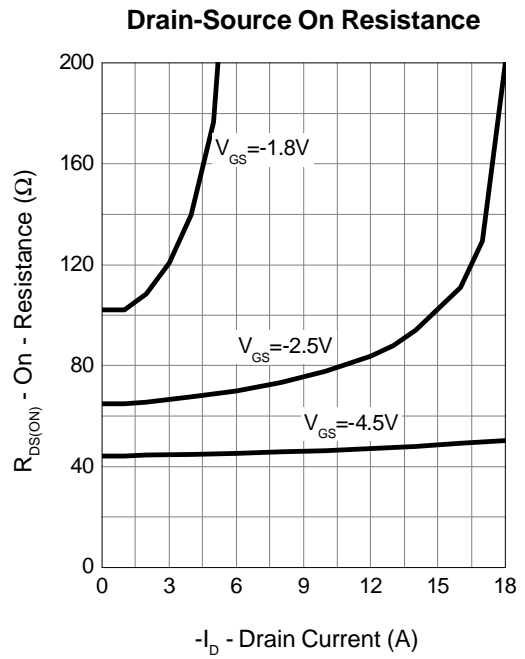
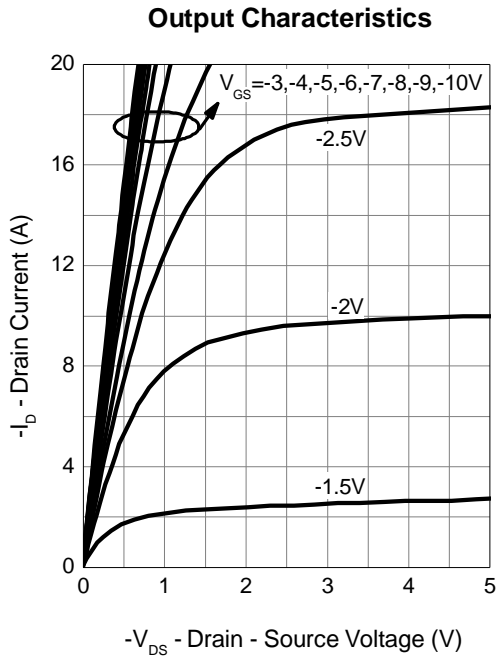
Safe Operation Area



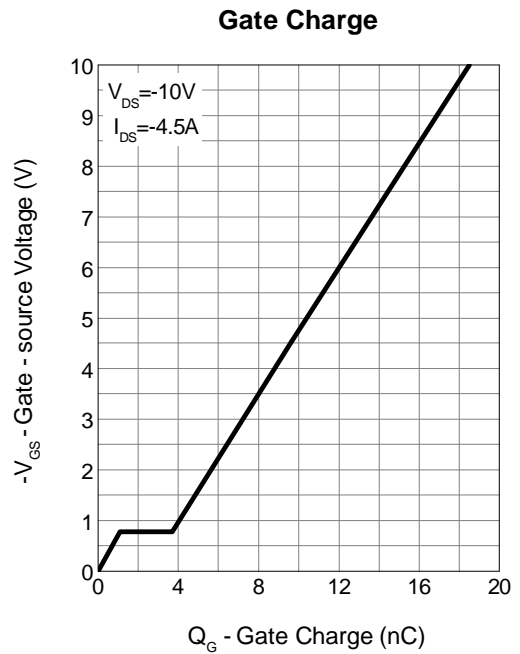
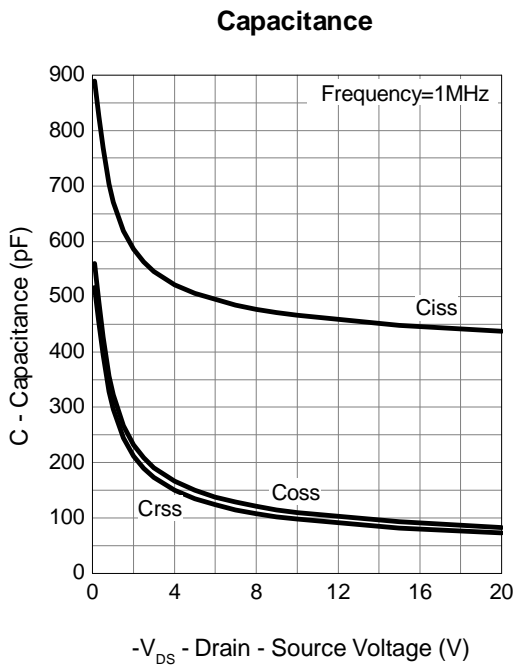
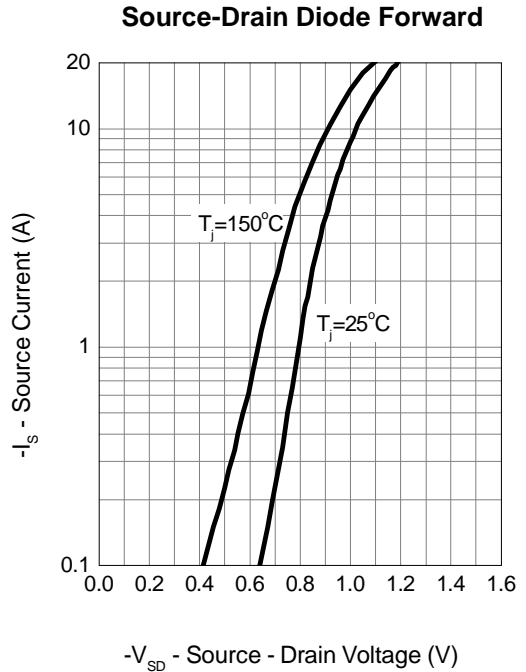
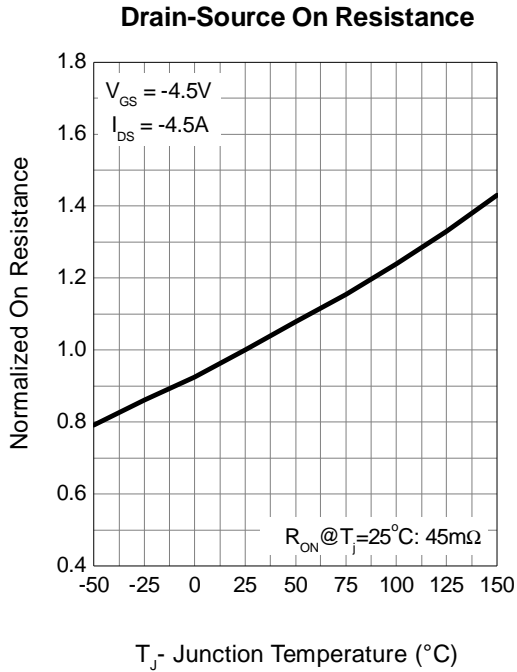
Thermal Transient Impedance



P Channel Typical Operating Characteristics (Cont.)

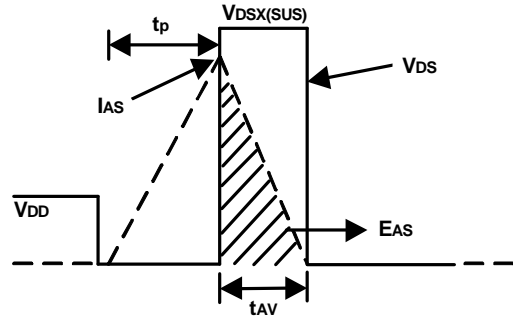
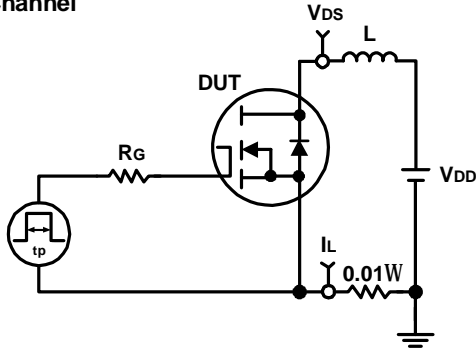


P Channel Typical Operating Characteristics (Cont.)

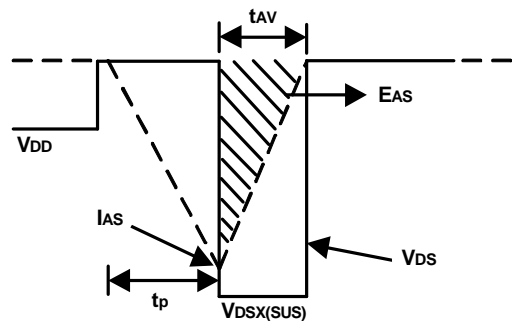
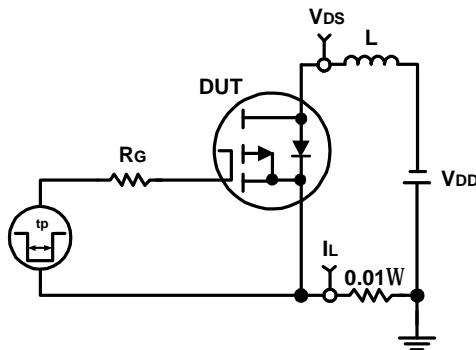


Avalanche Test Circuit and Waveforms

N Channel

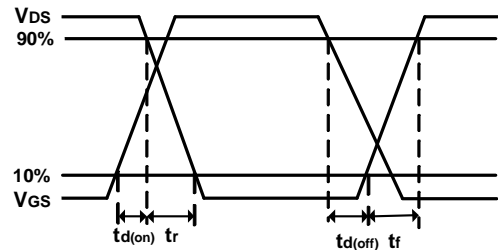
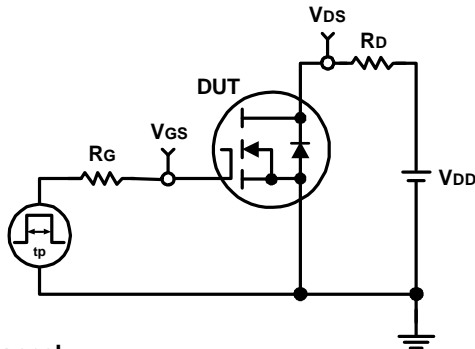


P Channel

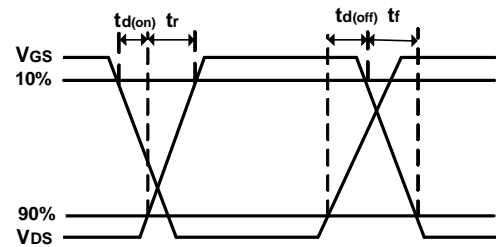
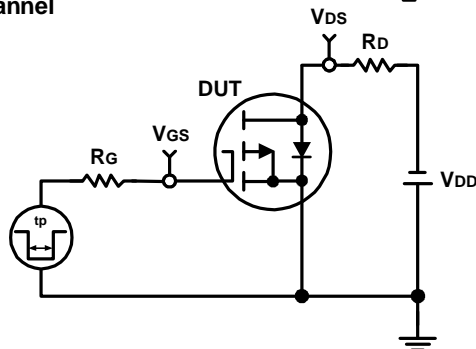


Switching Time Test Circuit and Waveforms

N Channel



P Channel



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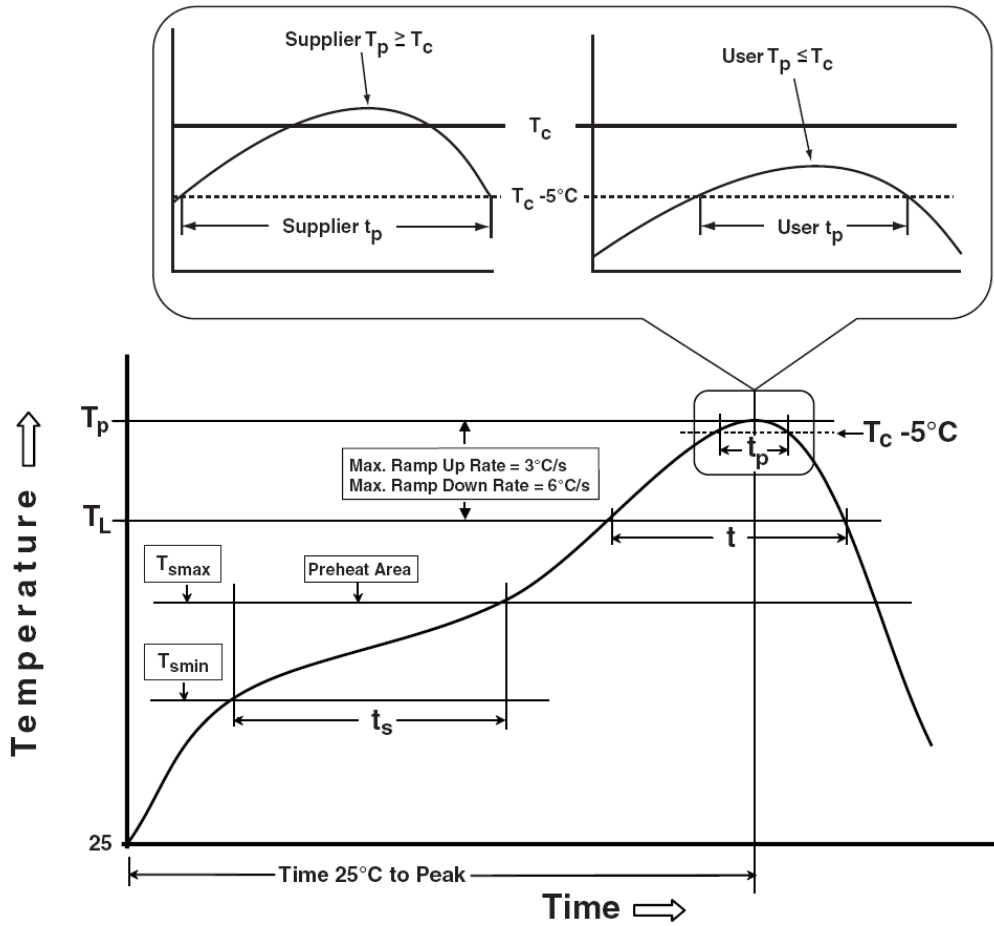
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Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak		
Temperature min (T_{smin})	100 °C	150 °C
Temperature max (T_{smax})	150 °C	200 °C
Time (T_{smin} to T_{smax}) (t_s)	60-120 seconds	60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C/second max.	3°C/second max.
Liquidous temperature (T_L)	183 °C	217 °C
Time at liquidous (t_L)	60-150 seconds	60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.
* Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum.		
** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.		

Table 1. SnPb Eutectic Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	1000 Hrs, 80% of VDS max @ T_{jmax}
HTGB	JESD-22, A108	1000 Hrs, 100% of VGS max @ T_{jmax}
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -65°C~150°C

Customer Service

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